

Application/Control No.	Applicant(s)/Patent under Reexamination
10/772,933	CHIOU, YIH-FANG
Examiner	Art Unit
Ephrem Alemu	2821

	SEAR	CHED	
Class	Subclass	Date	Examiner
315	119, 127, 121, 307, 306, 225,	4/14/2005	EA
315	224, 291	4/14/2005	EA
315	DIG. 7	4/14/2005	EA
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

DATE (14/2005	EXMR EA
·14/2005	EA
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